			Docket No.
CERTIFICATE OF TRANSMISSION BY FACSIMILE (37 CFR 1.8)			BUR920010195US1
Applicant(s): Chadwick	et al.		
Application No.	Filing Date	Examiner	Group Art Unit
10/065,694	11/11/2002	Kerveros, James C.	2133
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Docket No. BUR920010195US1

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Chadwick et al.

Group Art Unit: 2133

Filed: 11/11/2002

Examiner: Kerveros, James C.

Serial No.: 10/065,694

Title: METHOD FOR TESTING EMBEDDED DRAM ARRAYS

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

RESTRICTION ELECTION

In response to the Restriction Requirement dated June 14, 2004, Applicants hereby provisionally clect Group I, claims 1-10, drawn to a method of testing a DRAM, classified in class 714, subclass 710. This election is made with traverse, and Applicants hereby reserve the right to file a divisional application in connection with unclected claims 11-12, drawn to an apparatus for testing a multiplicity of embedded DRAM blocks by writing test data pattern into each DRAM block simultaneously and claims 13-20, drawn to an apparatus for testing a multiplicity of embedded DRAM blocks by writing test data pattern into each DRAM block sequentially.

With regard to the Restriction Requirement, Applicants respectfully submit that the subject matter of all claims 1-20 is sufficiently related that a thorough search for the subject matter of any one group of claims would encompass a search for the subject matter of the remaining claims. Thus, Applicants respectfully submit that the search and the examination of the entire application could be made without serious burden. See MPEP § 803, in which it is stated

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that "if the search and examination of the entire application can be made without serious burden, the Examiner <u>must</u> examine it on the merits, <u>even though it includes claims to independent or distinct inventions</u>" (emphasis added). Applicants respectfully submit that this policy should apply in the present application in order to avoid unnecessary delay and expense to Applicants and duplicative examination by the Patent Office.

Should the Examiner require or request anything further from Applicants prior to examination, the Examiner is requested to contact Applicants' undersigned representative at the telephone number below. Otherwise, Applicants request early and favorable examination on the merits.

Date: 07/02/2004

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